1st Workshop on Intelligent Methods for Test and Reliability
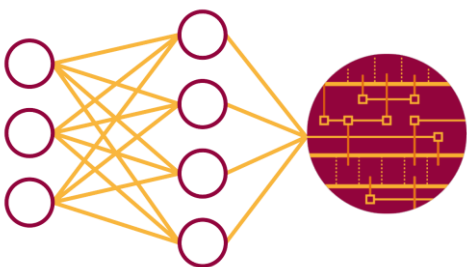
(co-located with IEEE European Test Symposium)

Barcelona, Spain

May 26-27

https://www.gs-imtr.uni-stuttgart.de/imtr22

Call for Papers

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Data collected during different test-related design, manufacturing, and operation steps bear huge potential that is heavily under-utilized today. As a consequence, test methods are undergoing a transformation triggered by the advent of next-generation artificial intelligence and data science technology. This workshop aims at bringing the core test community together with interdisciplinary researchers working on various facets of intelligent methods within the test flow. This workshop will leverage the interdisciplinary potentials to consider intelligent methods for test-related problems from the points of view of both: the test community and researchers working in other scientific areas, such as machine learning, data science, security, software engineering, and visualization.

The workshop invites submissions on, but not limited to, the following topics:

- Intelligent methods, including machine learning, data and visual analytics, for test and reliability problems (design for testability, post-silicon validation, test application, yield optimization, fault-tolerant operation)
- Secure and privacy-preserving semiconductor testing
- Intelligent techniques for system-level test
- Data-driven software engineering for handling test-related data
- Intelligent solutions for ultra-high speed, ultra-high data rate test application

A submission can describe a novel scientific result, provide a position statement about a new and relevant problem, or report a case study on practical experiences with a technique from the list above. The submissions should not be formally published in the past. The workshop will have no formal proceedings, so authors will be free to resubmit their work to conferences or journals. Accepted papers can, at the discretion and with an approval of their authors, be published on the workshop's website.

Author instructions: Submissions in form of full 6-page papers or 1-2 page extended abstracts (in IEEE double-column format, either A4 or US Letter) should be submitted through EasyChair:

https://easychair.org/conferences/?conf=imtr22

Key dates:

Submission deadline: ~~March 25, 2022~~ April 08, 2022 (extended)

Acceptance notification: April 20, 2022

PDF file for publishing on the workshop's website (optional): May 10, 2022

Registration: This workshop is co-located with the IEEE European Test Symposium and will use its registration facilities. Please register through the ETS website: https://ets2022.upc.edu/

Workshop organizers: This workshop is organized by the Graduate School Intelligent Methods for Test and Reliability (GS-IMTR), a joint program between the University of Stuttgart and Advantest.

GS-IMTR
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